

Revisiting (ϵ, γ, τ) -similarity learning for domain adaptation

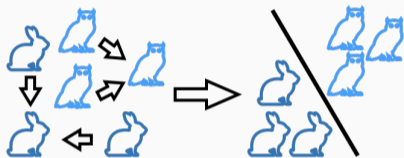
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Similarity learning

Learn a similarity function tailored to an observed data sample



Similarity learning

Learn a similarity function tailored to an observed data sample



Goal

Analyze similarity learning in domain adaptation context



Labeled source sample $S \sim \mathcal{S}$

Unlabeled target sample $T \sim \mathcal{T}$

same deterministic labeling function

What we know already (Balcan et al. 2008)

Definition

K is (ϵ, γ, τ) -good similarity for \mathcal{S} if

- ▶ $(1 - \epsilon)$ fraction of instances are on average **more similar** to landmarks with the **same label** by a margin γ **at least**
 - ▶ **fraction of landmark** instances $\geq \tau$
-

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Definition

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Theorem

If K is (ϵ, γ, τ) -good for S then one can **draw** $\{x_1, \dots, x_L\}$ from S and **build a mapping** $\phi : x \mapsto (K(x, x_1), \dots, K(x, x_L))$ that makes it **linearly separable** with a **large margin**

- ✓ **Generalization of the kernel trick!**
- ✓ **Several algorithms that minimize ϵ !**

Idea

Introduce (ϵ, γ) -goodness for $(\mathcal{S}, \mathcal{R})$ with data $\sim \mathcal{S}$ and landmarks $\sim \mathcal{R}$ (potentially $\mathcal{R} \neq \mathcal{S}$)

Our contribution

Idea

Introduce (ϵ, γ) -goodness for $(\mathcal{S}, \mathcal{R})$ with data $\sim \mathcal{S}$ and landmarks $\sim \mathcal{R}$ (potentially $\mathcal{R} \neq \mathcal{S}$)

Theorem

If \mathbf{K} is (ϵ, γ) -good for $(\mathcal{S}, \mathcal{R})$ and μ **dominates** \mathcal{S} and \mathcal{T} then \mathbf{K} is $(\epsilon + \epsilon', \gamma)$ -good for $(\mathcal{T}, \mathcal{R})$ with

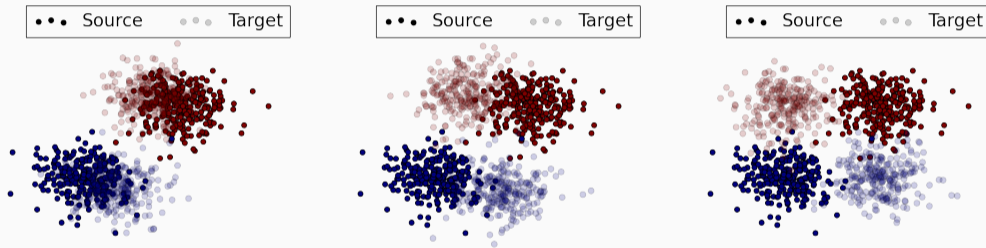
$$\epsilon' = \text{L}^1 \text{ distance between } \mathcal{S} \text{ and } \mathcal{T} \times \text{Worst margin achieved by } \mathbf{K} \text{ on } x \sim \mu, \text{ if } \mathcal{T} \not\ll \mathcal{S}$$

and

$$\epsilon' = \chi^2 \text{ distance between } \mathcal{S} \text{ and } \mathcal{T} \times \text{Worst margin achieved by } \mathbf{K} \text{ on } x \sim \mathcal{S} \times \epsilon \text{ on source } \mathcal{S}, \text{ if } \mathcal{T} \ll \mathcal{S}$$

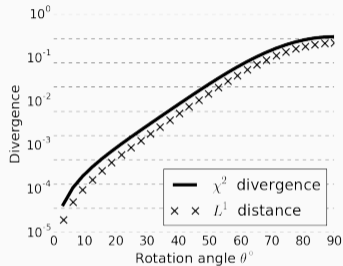
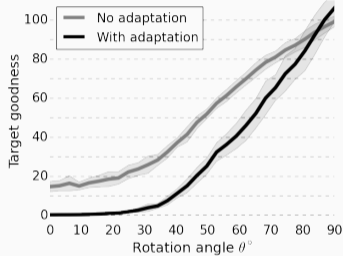
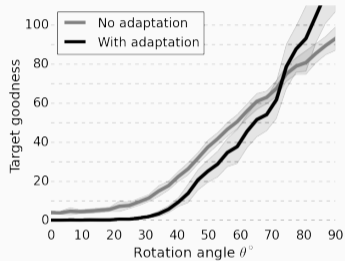
✓ **Multiplicative dependence of the target error on the source one!**

Empirical evaluations



Generated data for (**left**) 30°, (**middle**) 60°, (**right**) 90° degrees rotation

Empirical evaluations



Results for (left) $\mathcal{T} \ll \mathcal{S}$, (middle) $\mathcal{T} \ll \mathcal{S}$ and (right) divergence evolution

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poster #152 !**

(spoiler: post-doc position available)